

KGD TESTER

KGD tests made easy





INFOTECH KGD TESTER

KGD testing introduces distinct electrical, mechanical, and physical challenges. To meet these demands, we developed an all-in-one solution in partnership with VX Instruments.

We provide the handler and take full responsibility for overall system integration, while VX Instruments supplies the tester and other required sub-systems.

This best-of-breed approach removes typical customer pain points associated with complex integration and multi-supplier coordination. With a fully aligned KGD test line, we enable smooth implementation and help extend the limits of today's testing performance.



Static and dynamic test in a one-step-process



Flexible input and output options



High power testing up to 3`000 V / 20`000 A



Fully automated single die testing up to 2`400 UPH



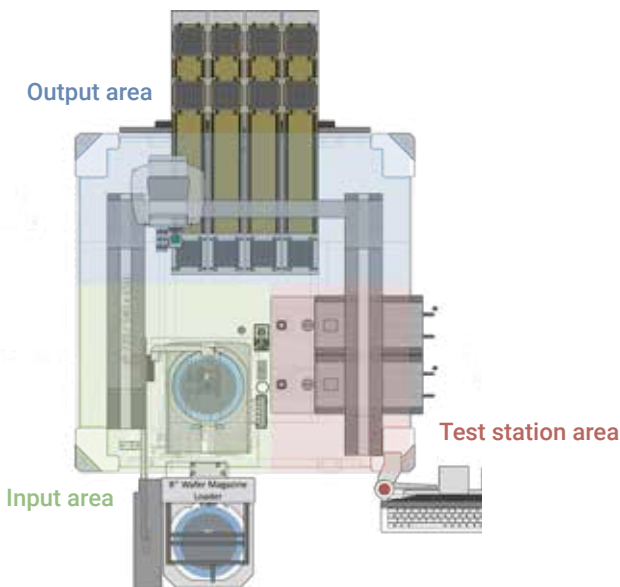
POWER MODULE TESTING

Static and dynamic tests, along with partial-discharge measurements to confirm insulation integrity, require specialized test equipment and strictly controlled environments, including generators capable of supplying high voltages and high currents.

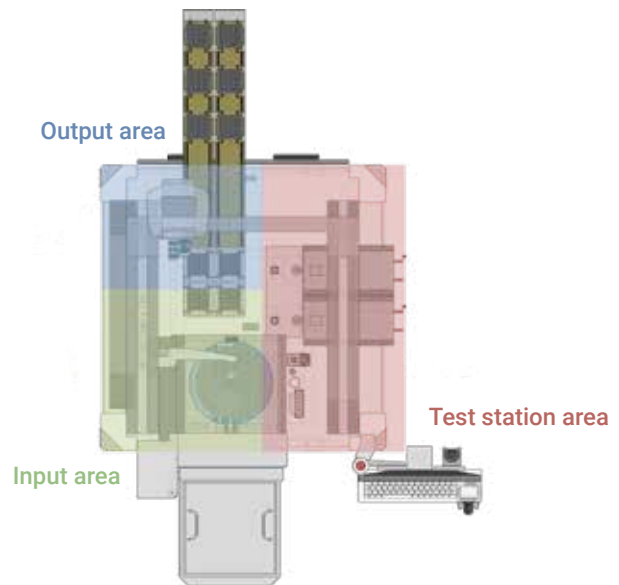
The test items are moved into a test chamber, flooded with CO₂, guided to the test system, and connected via a contact unit. While one module is under test, the handling system can simultaneously unload a second, finished module and place it into the required output format.

KGD TESTER LAYOUT

KGD Test Handler 8" Wafer



KGD Test Handler 12" Wafer



HANDLING OPTIONS

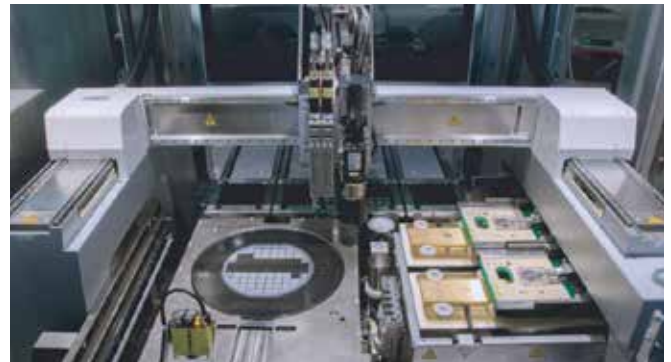
INPUT OPTIONS

Pick from:

- Wafer handler for 6", 8" or 12"
- Tape and reel feeder

Different packages with single positions or stack feeder:

- 2" or 4" waffle pack
- 2" or 4" Gel-Pak
- Jedec tray
- Custom tray form



OUTPUT OPTIONS

Separation in quality grades based on test results for all possible variants. Placement into different packages with single positions or stack feeder:

- 2" or 4" waffle pack
- 2" or 4" Gel-Pak
- Jedec tray
- Custom tray form

Placement onto:

- Blue foil (wafer frame)
- Blister tape (sealing with cover tape)

TESTER KEY FEATURES

- **High accuracy & low noise:** Complete guarding to reduce leakage, sensing directly at the DUT, isolated measurement units for highly precise high-side measurements.
- **Very short test times:** Pulsed currents up to 2400 A / 100 μ s, high-speed switching matrix, test time < 500 ms, reduced index time by combining dynamic and static tests on one station.
- **High performance:** Up to 3'000 V / 20,000 A, ultra-low parasitic inductance down to 5 nH thanks to cable-free testhead contacting, wide bandwidth.
- **Low thermal impact:** Low power consumption minimizes heating effects on the DUT and connections.
- **Highly flexible & modular:** Customizable configurations (e.g., 3'000 V / 10'000 A or 1'500 V / 20'000 A), fast integration, easy maintenance, high commonality for spare parts.



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